

Search Notes

Application/Control No.

10/766,974

Examiner

James D. Stein

Applicant(s)/Patent under
Reexamination

SCHEUER ET AL.

Art Unit

2874

SEARCHED

Class	Subclass	Date	Examiner
385	14, 27, 40, 129-132	12/19/2005	JDS
372	94	12/19/2005	JDS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See attached EAST search history	12/19/2005	JDS
IEEE and INSPEC: radial, bragg grating	12/19/2005	JDS